


Search Notes 	Application/Control No. 10816860	Applicant(s)/Patent Under Reexamination SHIN, SUNG SU
	Examiner Haney, Richale L	Art Unit 3765


Notes	Date	Examiner
-------	------	----------

See EAST printout

10/23/2006


RLH

U.S. Patent and Trademark Office	Part of Paper No.:
----------------------------------	--------------------

<i>Interference Searched</i> 	Application/Control No. 10816860	Applicant(s)/Patent Under Reexamination SHIN, SUNG SU
	Examiner Haney, Richale L	Art Unit 3765

Class	SubClass	Date	Examiner
EAST .clm. search		10/23/2006	RLH

U.S. Patent and Trademark Office	Part of Paper No.:
----------------------------------	--------------------

<p>Searched</p> 	<p>Application/Control No.</p> <p>10816860</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>SHIN, SUNG SU</p>
	<p>Examiner</p> <p>Haney, Richale L</p>	<p>Art Unit</p> <p>3765</p>

Class	SubClass	Date	Examiner
2	181,183,184,171,200.1	10/23/2006	RLH

U.S. Patent and Trademark Office	Part of Paper No.:
----------------------------------	--------------------